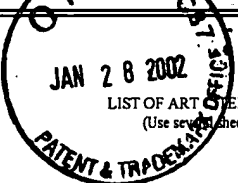
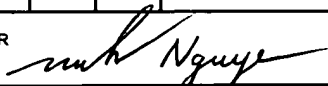


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1680		SERIAL NO. 09825,961	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE April 3, 2001		GROUP 2829	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VA	AA	5,886,863	03/23/99	NAGASAKI et al			
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
EXAMINER <i>muh Nguyen</i>				DATE CONSIDERED 07/23/2002			
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Form PTO-1449					ATTY. DOCKET NO. M122-1680		SERIAL NO. 09/825,664	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ARTS CITED BY APPLICANT (Use seven sheets if necessary)					APPLICANT David R. Hembree		FILING DATE April 3, 2001	
					GROUP 2858		2829	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
VN	AA	3,440,407	4/22/69	Golstos et al.				
	AB	3,614,345	10/19/71	Quinn				
	AC	3,683,306	8/8/72	Bulthius et al.				
	AD	4,332,081	6/1/82	Francis				
	AE	4,518,944	5/21/85	Faris				
	AF	4,703,555	11/3/87	Hubner				
	AG	5,141,334	8/25/92	Castles				
	AH	5,347,869	9/20/94	Shie et al.				
	AI	5,406,109	4/11/95	Whitney				
	AJ	5,436,646	7/25/95	McArthur et al.				
	AK	5,446,437	8/29/95	Bantien et al.				
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
VN	AL	2336778	7/1977	France				
VN	AM	56-12521	2/1981	Kobayashi, Japan				
VN	AN	2-268462	11/1990	Yamanishi, Japan				
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
VN	AR	Application Guide Temperature Sensors, Watlow Electrical Manufacturing Company Catalog, pp. 775-778, 1992/1993.						
VN	AS	In-Situ survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum, Lechevalier, LeHuroc, Richon, Sarrailh, & Gossault, J. Phys. III France, Vol. 3, pp. 409-418, 04/93 (Abstract only).						
VN	AT	Temperature Metrology for CD Control in DUV Lithography, Jeffrey Parker and Wayne Resken, pp. 111-112, 114, 116, 09/17/97.						
EXAMINER				DATE CONSIDERED				
				07/23/2002				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1680		SERIAL NO. 09/825,664	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David Hembree		FILING DATE April 3, 2001	
				GROUP 2829			

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA	5,612,574	3/18/97	Summerfelt et al.			
	AB	5,719,333	2/17/98	Hosoi et al.			
	AC	5,831,333	11/3/98	Malladi et al.			
	AD	5,919,548	7/6/99	Barron et al.			
	AE	5,551,283	9/3/96	Manaka et al.			
	AF	5,492,011	2/20/96	Amano et al.			
	AG						
	AH						
	AJ						

FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AK							
AL							
AM							
AN							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
VN	AP		"NTC and PTC Thermistors"; <a href="http://www.thermodisc.com/ntcptc.html">http://www.thermodisc.com/ntcptc.html</a> ; 1/7/98; 2 pages.
VN	AR		"DI-5B35 Linearized 4-Wire RTD Input"; ; <a href="http://www.dataq.com/di5b35.html">http://www.dataq.com/di5b35.html</a> ; 1/7/98; 2 pages.
VN	AS		"RTD"; <a href="http://www.mtisensors.com/rtds.html">http://www.mtisensors.com/rtds.html</a> ; 1/7/98; 3 pages.
VN	AT		"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; <a href="http://www.minco.com/s17624nr.html">http://www.minco.com/s17624nr.html</a> ; 1/7/98; 1 page.
VN	AU		"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology; Second Edition; S. Wolf et al.; 2000; pps 22-25 and pps. 841-845.

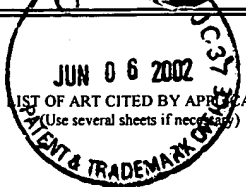
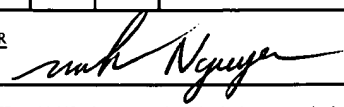
  

EXAMINER <i>anh Nguyen</i>	DATE CONSIDERED 07/23/2002
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Form PTO-1449				ATTY. DOCKET NO. M122-1680		SERIAL NO. 09/825,664	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		FILING DATE April 3, 2001	
				GROUP 2829			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
VN	AA	6,004,471	12/21/1999	Chuang			
VN	AB	5,550,526	8/27/1996	Mottahead			
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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	AJ						
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	AL						
EXAMINER 				DATE CONSIDERED 07/23/2002			
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